

ETR0202\_005

#### Voltage Detectors, Delay Circuit Built-In

## ■GENERAL DESCRIPTION

The XC61F series are highly accurate, low power consumption voltage detectors, manufactured using CMOS and laser trimming technologies. A delay circuit is built-in to each detector.

Detect voltage is extremely accurate with minimal temperature drift.

Both CMOS and N-ch open drain output configurations are available.

Since the delay circuit is built-in, peripherals are unnecessary and high density mounting is possible.

#### APPLICATIONS

- Microprocessor reset circuitry
- Memory battery back-up circuits
- Power-on reset circuits
- Power failure detection
- System battery life and charge voltage monitors
- Delay circuitry

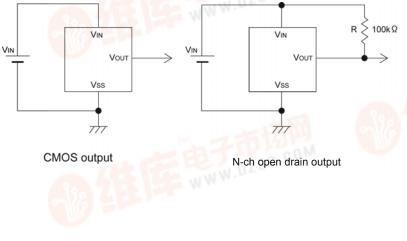


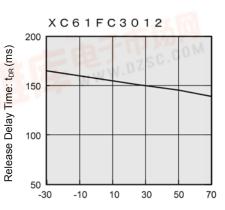
FEATURES	
Highly Accurate	: ± 2%
Low Power Consumption	: 1.0 µ A(TYP.)[ VIN=2.0V ]
Detect Voltage Range	: 1.6V ~ 6.0V in 0.1V increments
<b>Operating Voltage Range</b>	: 0.7V ~ 10.0V
Detect Voltage Temperat	ture Characteristics
	:±100ppm/°C(TYP.)
Built-In Delay Circuit	: ① 1ms ~ 50ms
	② 50ms ~ 200ms
	③ 80ms ~ 400ms
Output Configuration	: N-ch open drain output or CMOS
Packages	: SOT-23
	: SOT-89
	: TO-92
Environmentally Friendly	: EU RoHS Compliant, Pb Free

\* No parts are available with an accuracy of ± 1% WWW.DZSC.COM

## ■TYPICAL APPLICATION CIRCUITS

#### TYPICAL PERFORMANCE CHARACTERISTICS



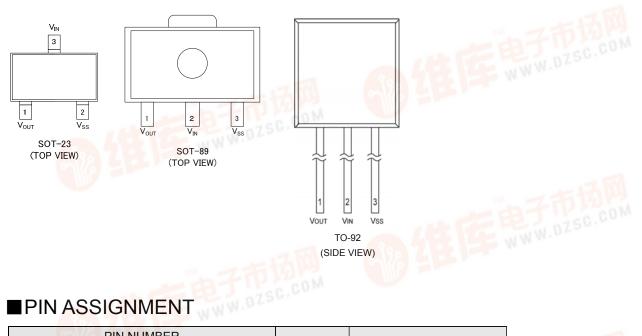


Release Delay Time vs. Ambient Temperature

Ambient Temperature:Ta(°C)



## **■**PIN CONFIGURATION



PIN NUMBER			PIN NAME	FUNCTION	
SOT-23	SOT-89	TO-92		FUNCTION	
3	2	2	V <sub>IN</sub>	Supply Voltage Input	
2	3	3	V <sub>SS</sub>	Ground	
1	1	1	Vout	Output	









## ■PRODUCT CLASSIFICATION

Ordering Information

#### XC61F (1)(2)(3)(4)(5)(6)(7)-(8)<sup>(\*1)</sup>

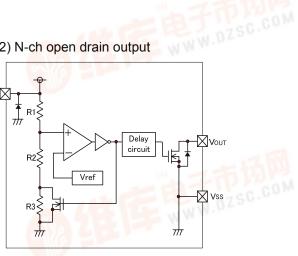
<ul> <li>Ordering Infor</li> </ul>	mation			
XC61F 1234	<u>567-8</u> (*1)			
DESIGNATOR	ITEM	SYMBOL	DESCRIPTION	
1	Output Configuration	С	CMOS output	
		N	N-ch o <mark>pen dra</mark> in output	
23	Detect Voltage	16 ~ 60	e.g. 2.5 <mark>V →</mark> ②2 , ③5	
23		0210-00	e.g. 3.8V → ②3, ③8	
~32		1	50ms ~ 200ms	
4	Release Output Delay	4	80ms ~ 400ms	
		5	1ms ~ 50ms	
5	Detect Accuracy	2	Within ± 2.0%	
	Packages (Order Unit)	MR	SOT-23 (3,000/Reel)	
		MR-G	SOT-23 (3,000/Reel)	
		PR	SOT-89 (1,000/Reel)	
67-8 <sup>(*1)</sup>		PR-G	SOT-89 (1,000/Reel)	
		TH	TO-92 Taping Type: Paper type (2,000/Tape)	
		TH-G	TO-92 Taping Type: Paper type (3,000/Tape)	
		ТВ	TO-92 Taping Type: Bag (500/Bag)	
		TB-G	TO-92 Taping Type: Bag (500/Bag)	

<sup>(1)</sup> The "-G" suffix indicates that the products are Halogen and Antimony free as well as being fully RoHS compliant.



## (1) CMOS output **1** R1 € Delay ∐∨о∪т circuit R2 Vref -🖄 Vss R3 $\frac{1}{2}$ WWW.DZSC.COM

(2) N-ch open drain output





# XC61F Series

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## ■ABSOLUTE MAXIMUM RATINGS

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PARAME	TER	SYMBOL	RATINGS	UNITS
Input Vol	tage	V <sub>IN</sub>	V <sub>SS</sub> -0.3~12.0	V
Output Current		Ι <sub>ουτ</sub>	50	mA
	CMOS		V <sub>SS</sub> -0.3 ~ V <sub>IN</sub> + 0.3	DZSC.
Output Voltage	N-ch open drain	Vout	V <sub>SS</sub> -0.3 ~ 9	V
	output	17.10		
Power Dissipation	SOT-23	1 VO COM	250	
	SOT-89	SC Pd	500	mW
	TO-92		300	
Operating Temperature Range		Topr	-30~+80	°C
Storage Temperature Range		Tstg	-40~+125	°C

## ■ ELECTRICAL CHARACTERISTICS

Ta = 25°C

PARAI	METER	SYMBOL	CONDITIONS		MIN.	TYP.	MAX.	UNITS	CIRCU
Detect	Voltage	VDF	-TD IS COM		VDF(T) x 0.98	VDF(T)	VDF(T) x 1.02	V	1
Hystere	sis Width	VHYS	1.02501		Vdf x 0.02	VDF x 0.05	Vdf x 0.08	V	1
Supply Current		·		VIN = 1.5V	-	0.9	2.6	554	
				VIN = 2.0V	-	1.0	3.0		
		lss		VIN = 3.0V	-	1.3	3.4	μA	2
				$V_{IN} = 4.0V$		1.6	3.8		
				VIN = 5.0V		2.0	4.2		
Operatin	g Voltage	Vin	VDF= 1.6V to	o 6.0V	0.7	-	10.0	V	1
			Mag	$V_{IN} = 1.0V$	1.0	2.2	-		
		IOUT	DZSC.COM	VIN = 2.0V	3.0	7.7	-		
			N-ch VDs =0.5V	VIN = 3.0V	5.0	10.1	-	mA	3
Output	Current			VIN = 4.0V	6.0	11.5	-		
				VIN = 5.0V	7.0	13.0	17		
		P-ch VDS=2.1V (CMOS Output)	VIN = 8.0V		-10.0	-2.0	COM	4	
CMOS Leak Output		I <sub>LEAK</sub>	$V_{\rm H} = 10.0 V_{\odot} V_{\odot}$	ur = 10.0V		0.01	1.02.0	μA	3
Current Nch Oper Drain	Nch Open Drain	ILEAK	$V_{IN} = 10.0V, V_{OUT} = 10.0V$		-	0.01	0.1	μΑ	3
Detect Voltage Temperature Characteristics		ΔV <sub>DF</sub> / (ΔTopr·V <sub>DF</sub> )	1.DZ50.		-	±100	-	ppm/ °C	1
Release Delay Time				50	-	200			
		tDR VIN changes from 0.6V to 10V		80	14	400	ms	5	
	(VDR $\rightarrow$ VOUT inversion)				1				50

VDF (T): Setting detect voltage value Release Voltage: VDR = VDF + VHYS

\* Release Delay Time: 1ms to 50ms & 80ms to 400ms versions are also available.

Note: The power consumption during power-start to output being stable (release operation) is 2 µ A greater than it is after that period (completion of release operation) because of delay circuit through current.





#### ■OPERATIONAL EXPLANATION

#### CMOS output

(1) When a voltage higher than the release voltage  $(V_{DR})$  is applied to the voltage input pin  $(V_{IN})$ , the voltage will gradually fall. When a voltage higher than the detect voltage  $(V_{DF})$  is applied to VIN, output  $(V_{OUT})$  will be equal to the input at VIN.

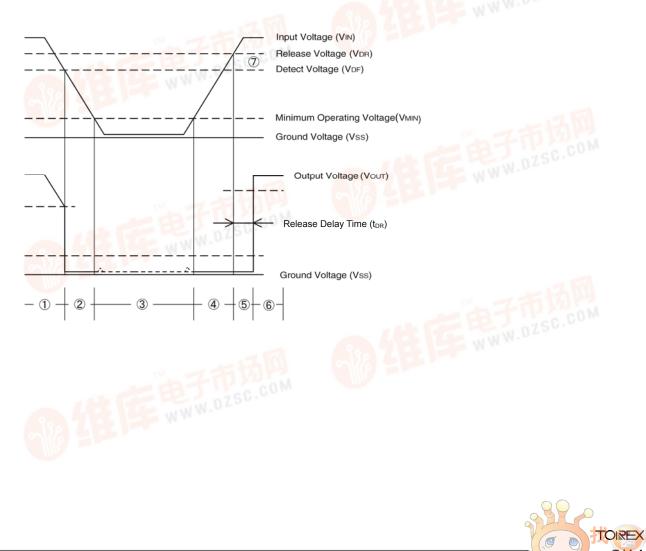
Note that high impedance exists at V<sub>OUT</sub> with the N-ch open drain output configuration. If the pin is pulled up, V<sub>OUT</sub> will be equal to the pull up voltage.

- When V<sub>IN</sub> falls below V<sub>DF</sub>, V<sub>OUT</sub> will be equal to the ground voltage (V<sub>SS</sub>) level (detect state). Note that this also applies to N-ch open drain output configurations.
- ③ When V<sub>IN</sub> falls to a level below that of the minimum operating voltage (V<sub>MIN</sub>) output will become unstable. Because the output pin is generally pulled up with configurations, output will be equal to pull up voltage.
- 4 When  $V_{IN}$  rises above the  $V_{SS}$  level (excepting levels lower than minimum operating voltage),  $V_{OUT}$  will be equal to  $V_{SS}$  until  $V_{IN}$  reaches the  $V_{DR}$  level.
- (5) Although VIN will rise to a level higher than VDR, VOUT maintains ground voltage level via the delay circuit.
- ⑥ Following transient delay time, V<sub>IN</sub> will be output at V<sub>OUT</sub>. Note that high impedance exists with the N-ch open drain output configuration and that voltage will be dependent on pull up.

#### Notes:

- 1. The difference between  $V_{DR}$  and  $V_{DF}$  represents the hysteresis range.
- 2. Release delay time (t<sub>DR</sub>) represents the time it takes for V<sub>IN</sub> to appear at V<sub>OUT</sub> once the said voltage has exceeded the V<sub>DR</sub> level.

#### Timing Chart



# XC61F Series

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### ■DIRECTIONS FOR USE

Notes on Use

- 1. Please use this IC within the stated absolute maximum ratings. For temporary, transitional voltage drop or voltage rising phenomenon, the IC is liable to malfunction should the ratings be exceeded.
- 2. When a resistor is connected between the V<sub>IN</sub> pin and the power supply with CMOS output configurations, oscillation may occur as a result of voltage drops at R<sub>IN</sub> if load current (I<sub>OUT</sub>) exists. It is therefore recommend that no resistor be added. (refer to Oscillation Description (1) below)
- 3. When a resistor is connected between the V<sub>IN</sub> pin and the power supply with CMOS output configurations, irrespective of N-ch output configurations, oscillation may occur as a result of through current at the time of voltage release even if load current (I<sub>OUT</sub>) does not exist. (refer to Oscillation Description (2) below)
- 4. If a resistor ( $R_{IN}$ ) must be used, then please use with as small a level of input impedance as possible in order to control the occurrences of oscillation as described above. Further, please ensure that  $R_{IN}$  is less than 10k $\Omega$  and that  $C_{IN}$  is more than 0.1  $\mu$  F, please test with the actual device. However, N-ch open drain output only. (Figure 1).
- 5. With a resistor RIN connected between the V<sub>IN</sub> pin and the power supply, the V<sub>IN</sub> pin voltage will be getting lower than the power supply voltage as a result of the IC's supply current flowing through the V<sub>IN</sub> pin.
- 6. Depending on circuit's operation, release delay time of this IC can be widely changed due to upper limits or lower limits of operational ambient temperature.
- 7. Torex places an importance on improving our products and its reliability. However, by any possibility, we would request user fail-safe design and post-aging treatment on system or equipment.

#### Oscillation Description

(1) Oscillation as a result of load current with the CMOS output configuration:

When the voltage applied at power supply, release operations commence and the detector's output voltage increases. Load current (IOUT) will flow through RL. Because a voltage drop (RIN x IOUT) is produced at the RIN resistor, located between the power supply and the VIN pin, the load current will flow via the IC's VIN pin. The voltage drop will also lead to a fall in the voltage level at the VIN pin. When the VIN pin voltage level falls below the detect voltage level, detect operations will commence. Following detect operations, load current flow will cease and since voltage drop at RIN will disappear, the voltage level at the VIN pin will rise and release operations will begin over again.

Oscillation may occur with this " release - detect - release " repetition.

Further, this condition will also appear via means of a similar mechanism during detect operations.

(2) Oscillation as a result of through current:

Since the XC61F series are CMOS ICs, through current will flow when the IC's internal circuit switching operates (during release and detect operations). Consequently, oscillation is liable to occur during release voltage operations as a result of output current which is influenced by this through current (Figure 3). Since hysteresis exists during detect operations, oscillation is unlikely to occur.

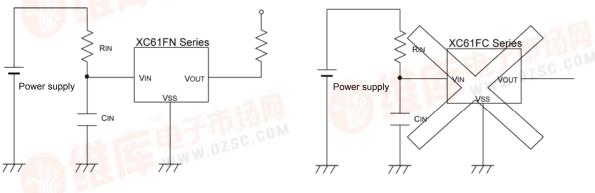


Figure 1. When using an input resistor

## ■DIRECTIONS FOR USE (Continued)

Oscillation Description (Continued)

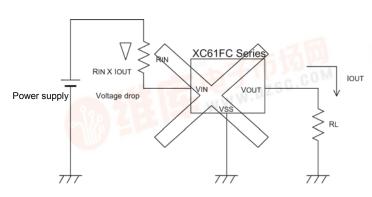
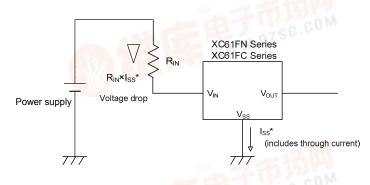


Figure 2. Oscillation in relation to output current



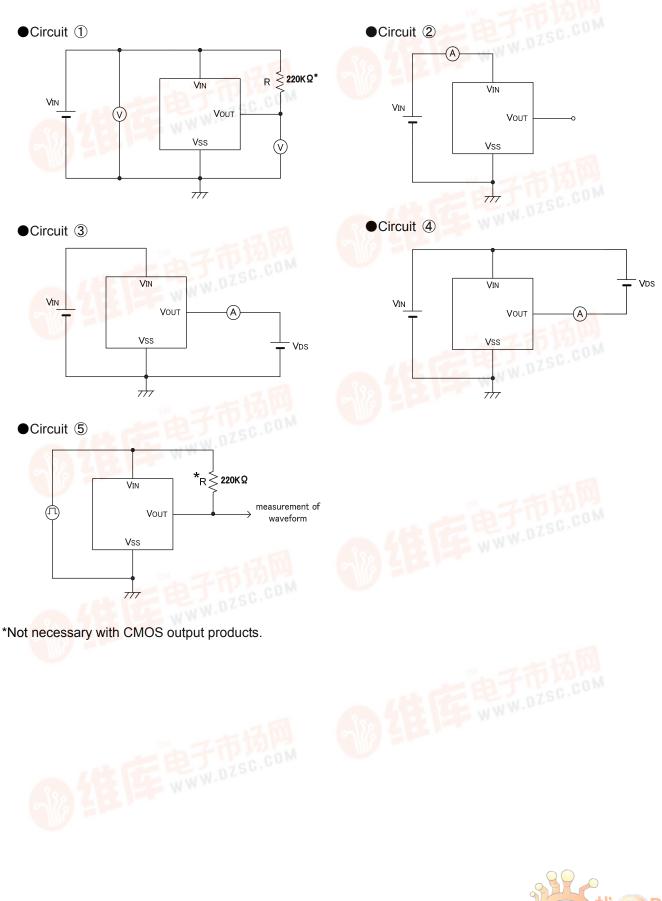
#### Figure 3. Oscillation in relation to through current



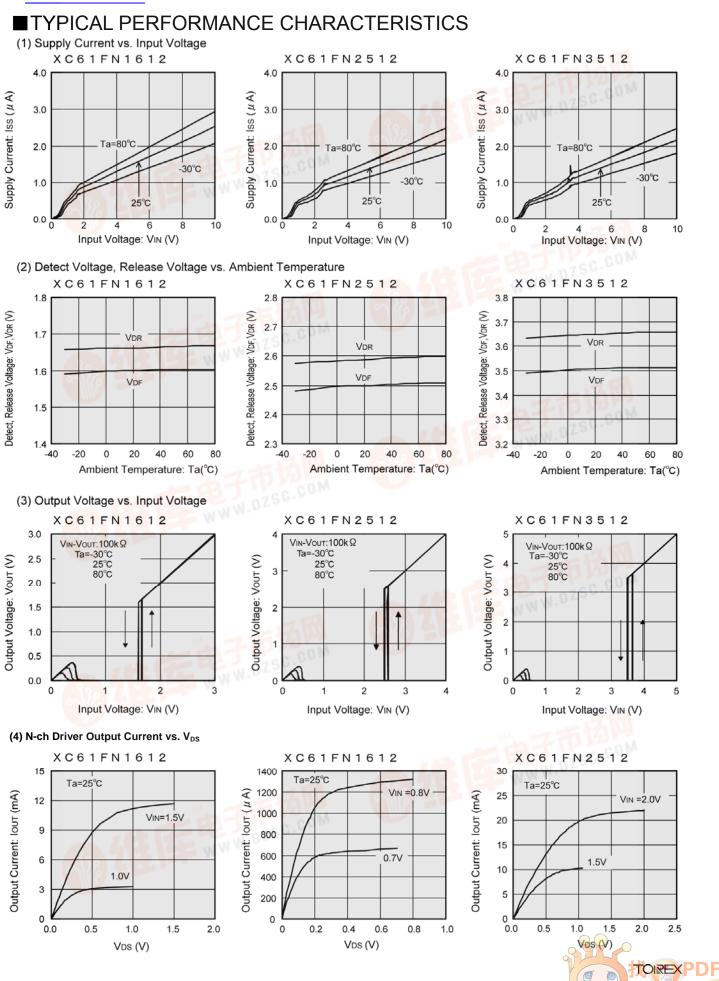




## ■TEST CIRCUITS

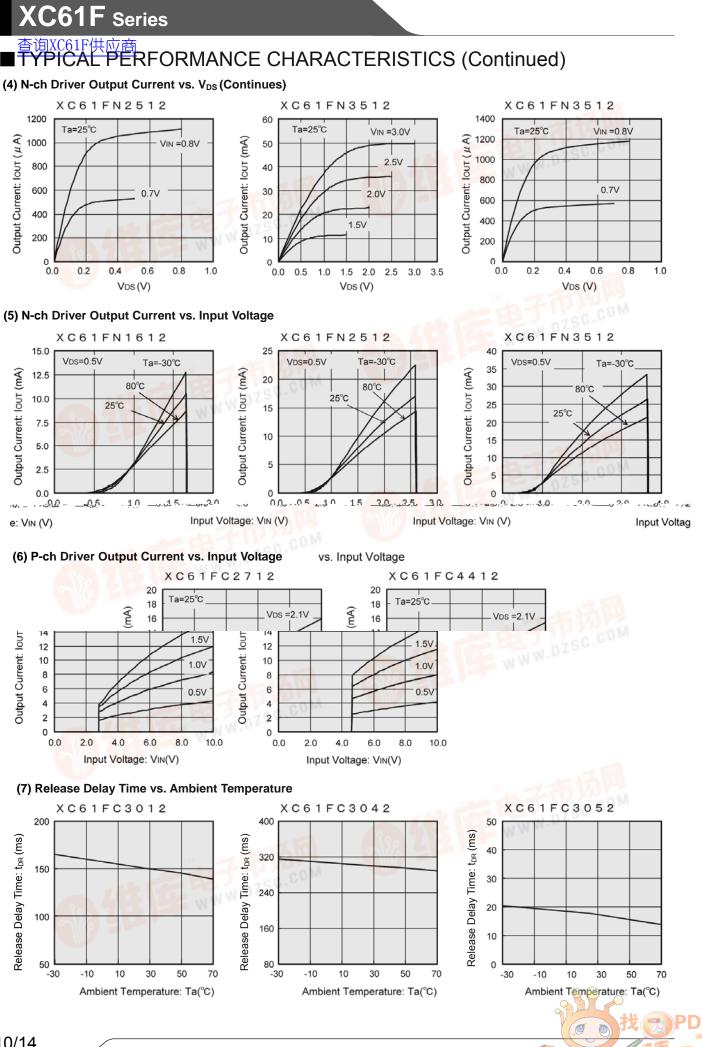


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## ■PACKAGING INFORMATION

